

Notice of References Cited

Application/Control No.

10/623,116

Applicant(s)/Patent Under
Reexamination
AGARWAL, SUMIT

Examiner

MARK FADOK

Art Unit

3625

Page 1 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0065515	03-2008	Bowler, Steve B.	705/28
*	B	US-2006/0149653	07-2006	Davis et al.	705/037
*	C	US-2005/0055299	03-2005	Chambers et al.	705/036
*	D	US-2004/0215467	10-2004	Coffman et al.	705/001
*	E	US-2004/0187091	09-2004	Parasnis et al.	717/104
*	F	US-2004/0153310	08-2004	Beck, Matthew	704/010
*	G	US-2004/0117294	06-2004	Ferraro et al.	705/037
*	H	US-2004/0083156	04-2004	Schulze, Arne	705/037
*	I	US-2004/0054649	03-2004	Mehregany, Mehran	707/001
*	J	US-2004/0044591	03-2004	Gilliland et al.	705/027
*	K	US-2004/0039735	02-2004	Ross et al.	707/3
*	L	US-2004/0019572	01-2004	Metz et al.	705/80
*	M	US-2003/0229522	12-2003	Thompson et al.	705/4

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/623,116		Applicant(s)/Patent Under Reexamination AGARWAL, SUMIT	
	Examiner MARK FADOK		Art Unit 3625	Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0212610	11-2003	Duffy et al.	705/26
*	B	US-2003/0208434	11-2003	Posner, Enrique	705/37
*	C	US-2003/0195824	10-2003	Duffy et al.	705/26
*	D	US-2003/0191677	10-2003	Akkiraju et al.	705/8
*	E	US-2003/0172022	09-2003	Coyne et al.	705/37
*	F	US-2003/0115099	06-2003	Burns et al.	705/14
*	G	US-2003/0036991	02-2003	Fortes et al.	705/37
*	H	US-2003/0028469	02-2003	Bergman et al.	705/37
*	I	US-2003/0014326	01-2003	Ben-Meir et al.	705/26
*	J	US-2003/0004656	01-2003	Bjornson, Carl C.	702/34
*	K	US-2002/0198818	12-2002	Scott et al.	705/37
*	L	US-2002/0188554	12-2002	Holbrook, Donald	705/37
*	M	US-2002/0171662	11-2002	Lee, Juhnyoung	345/593

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/623,116		Applicant(s)/Patent Under Reexamination AGARWAL, SUMIT	
	Examiner MARK FADOK		Art Unit 3625	Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0138289	09-2002	Thielges et al.	705/1
*	B	US-2002/0116281	08-2002	Costello et al.	705/26
*	C	US-2002/0112114	08-2002	Blair et al.	711/100
*	D	US-2002/0099612	07-2002	Seaman et al.	705/26
*	E	US-2002/0099598	07-2002	Eicher et al.	705/11
*	F	US-2002/0099580	07-2002	Eicher et al.	705/7
*	G	US-2002/0099579	07-2002	Stowell et al.	705/7
*	H	US-2002/0099578	07-2002	Eicher et al.	705/7
*	I	US-2002/0073114	06-2002	Nicastro et al.	707/500
*	J	US-2002/0038285	03-2002	Golden et al.	705/38
*	K	US-2002/0010685	01-2002	Ashby, David C.	705/80
*	L	US-2001/0032163	10-2001	Fertik et al.	705/37
*	M	US-7,107,268	09-2006	Zawadzki et al.	707/9

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/623,116		Applicant(s)/Patent Under Reexamination AGARWAL, SUMIT	
	Examiner MARK FADOK		Art Unit 3625	Page 4 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,072,061	07-2006	Blair et al.	358/1.15
*	B	US-6,952,219	10-2005	Lee, Juhnyoung	345/593
*	C	US-6,728,660	04-2004	Bjornson, Carl C.	702/185
*	D	US-6,526,423	02-2003	Zawadzki et al.	715/235
*	E	US-6,505,145	01-2003	Bjornson, Carl C.	702/185
*	F	US-5,802,493	09-1998	Sheflott et al.	705/1
*	G	US-5,765,138	06-1998	Aycock et al.	705/7
*	H	US-2005/0015305	01-2005	Agarwal, Sumit	705/026
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.